

Search Notes**Application/Control No.**

10/584,102

Examiner

CHRIS C. CHU

Applicant(s)/Patent under Reexamination

SCHEUCHER, HEIMO

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	E21,524, E23,179 & E21,599	7/2/2008	C.C.
257	797 & 48	7/2/2008	C.C.
257	238 & 68	7/2/2008	C.C.
257	620	7/2/2008	C.C.
430	22 & 5	7/2/2008	C.C.
430	311	7/2/2008	C.C.
324	633 & 765	7/2/2008	C.C.
324	754	7/2/2008	C.C.
356	399	7/2/2008	C.C.
438	033	7/2/2008	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
As same	as above	7/2/2008	C.C.

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; and IBM_TDB;	7/2/2008	C.C.